

December 1998

### 54LCX245

# Low Voltage Bidirectional Transceiver with 5V Tolerant Inputs and Outputs

### **General Description**

The LCX245 contains eight non-inverting bidirectional buffers with TRI-STATETM outputs and is intended for bus oriented applications. The device is designed for low voltage (3.3V)  $V_{\rm CC}$  applications with capability of interfacing to a 5V signal environment. The  $T/\overline{R}$  input determines the direction of data flow through the device. The  $\overline{OE}$  input disables both the A and B ports by placing them in a high impedance state.

The LCX245 is fabricated with an advanced CMOS technology to achieve high speed operation while maintaining CMOS low power dissipation.

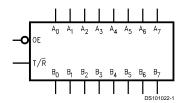
#### **Features**

- 5V tolerant inputs and outputs
- 9ns  $t_{PD}$  max,  $10\mu A I_{CCQ}$  max
- Power down high impedance inputs and outputs
- Supports live insertion/withdrawal
- 2.0V-3.6V V<sub>CC</sub> supply operation
- ±24 mA output drive
- Implements patented noise/EMI reduction circuitry
- Functionally compatible with the 54 series 245
- ESD performance:

Human body model > 2000V Machine model > 200V

■ Standard Microcircuit Drawing (SMD) 5962-97543

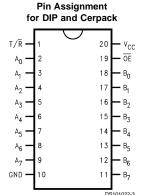
### **Logic Symbols**

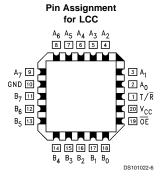


#### **Pin Descriptions**

Pin Names Description		
ŌĒ	Output Enable Input	
T/R	Transmit/Receive Input	
A <sub>0</sub> -A <sub>7</sub> B <sub>0</sub> -B <sub>7</sub>	Side A Inputs or 3-STATE Outputs	
B <sub>0</sub> -B <sub>7</sub>	Side B Inputs or 3-STATE Outputs	

### **Connection Diagram**





TRI-STATE® is a registered trademark of National Semiconductor Corporation.

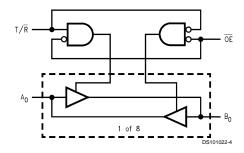
### **Truth Table**

	Inputs T/R		Outputs
	L L		Bus B <sub>0</sub> -B <sub>7</sub> Data to Bus A <sub>0</sub> -A <sub>7</sub>
	L H		Bus A <sub>0</sub> -A <sub>7</sub> Data to Bus B <sub>0</sub> -B <sub>7</sub>
	н х		HIGH Z State on A <sub>0</sub> -A <sub>7</sub> , B <sub>0</sub> -B <sub>7</sub> (Note 1)

H= High Voltage Level
L= Low Voltage Level
X= Immaterial
Z= High Impedance

Note 1: Unused bus terminals during HIGH Z State must be held HIGH or LOW.

### **Logic Diagram**



#### **Absolute Maximum Ratings** (Note 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage ( $V_{CC}$ ) -0.5V to +7.0V DC Input Voltage ( $V_{I}$ ) -0.5V to +7.0V

DC Input Diode Current (I<sub>IK</sub>)

 $V_{I}$  < GND -50 mA

DC Output Diode Current ( $I_{\rm OK}$ )

 $V_{O} < \text{GND}$  –50mA  $V_{O} \ge V_{CC}$  +50mA

DC Output Voltage (V<sub>O</sub>)

Output in High or Low State -0.5V to  $V_{CC} + 0.5V$  Output in TRI-STATE -0.5V to 7.0V

DC Output Source or Sink Current

(I<sub>O</sub>) ±50mA

DC  $V_{CC}$  or Ground Current  $\pm 200 mA$ 

Storage Temperature Range  $(T_{\text{STG}})$ 

Junction Temperature (T<sub>J</sub>)

DIP

## Recommended Operating Conditions (Note 3)

Supply Voltage (V<sub>CC</sub>)

 Operating
 2.0V to 3.6V

 Data Retention
 1.5V to 3.6V

 Input Voltage (V<sub>I</sub>)
 0V to 5.5V

Output Voltage (V<sub>O</sub>)

 $\begin{array}{lll} \mbox{High or Low State} & \mbox{OV to V}_{\mbox{CC}} \\ \mbox{TRI-STATE} & \mbox{OV to 5.5V} \end{array}$ 

Operating Temperature (T<sub>A</sub>)

54LCX –55°C to +125°C

Minimum Input Edge Rate (Δt/ΔV)

 $V_{IN}$  from 0.8V to 2.0V,  $V_{CC} = 3.0V$  Ons/V to 10ns/V

Note 2: The Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characresistics tables are not guaranteed at the Absolute Maximum Ratings. The "Recommended Operating Conditions" table will define the conditions for ac-

tual device operation.

Note 3: IO Absolute Maximum Rating must be observed.

#### **DC Electrical Characteristics**

Symbol	Parameter	Conditions	V <sub>cc</sub>	T <sub>A</sub> = -55°C to +125°C		Units
			(V)	Min	Max	1
V <sub>IH</sub>	HIGH Level Input Voltage		2.7-3.6	2.0		V
V <sub>IL</sub>	LOW Level Input Voltage		2.7-3.6		0.8	V
V <sub>OH</sub>	HIGH Level Output Voltage	I <sub>OH</sub> = -100 μA	2.7-3.6	V <sub>CC</sub> - 0.2		V
		I <sub>OH</sub> = -12 mA	2.7	2.2		V
		I <sub>OH</sub> = -12 mA	3.0	2.4		V
		I <sub>OH</sub> = -24 mA	3.0	2.2		V
V <sub>OL</sub>	LOW Level Output Voltage	I <sub>OL</sub> = 100 μA	2.7-3.6		0.2	V
		I <sub>OL</sub> = 12 mA	2.7		0.4	V
		I <sub>OL</sub> = 24 mA	3.0		0.55	V
I	Input Leakage Current	$0 \le V_I \le 5.5V$	2.7-3.6		±5.0	μA
V <sub>IKL</sub>	Clamp Diode Voltage	I <sub>M</sub> = -18mA	3.0		-1.2	V
I <sub>OZ</sub>	TRI-STATE I/O Leakage	0 ≤ V <sub>O</sub> ≤ 5.5V	2.7-3.6		±5.0	μA
		$V_I = V_{IH}$ or $V_{IL}$				
I <sub>CCZ</sub>	Supply Current Outputs TRI-STATE	V <sub>I</sub> = 5.5V or GND	2.7-3.6		10	μА
I <sub>OFF</sub>	Power-Off Leakage Current	V <sub>CC</sub> = 0V, V <sub>I</sub> = 0V, V <sub>M</sub> = 5.5V	0		100	μА
Icc	Quiescent Supply Current	V <sub>I</sub> = V <sub>CC</sub> or GND	2.7-3.6		10	μA
$\Delta I_{CC}$	Increase in I <sub>CC</sub> per Input	$V_{IH} = V_{CC} - 0.6V$	2.7-3.6		0.5	mA

-65°C to +150°C

175°C

### **AC Electrical Characteristics**

Symbol	Parameter	T <sub>A</sub> =	$T_A = -55^{\circ}C$ to +125°C, $C_L = 50$ pF, $R_L = 500\Omega$			
		V <sub>CC</sub> = 3.	V <sub>CC</sub> = 3.3V ± 0.3V		V <sub>CC</sub> = 2.7V	
		Min	Max	Min	Max	
t <sub>PHL</sub>	Propagation Delay	1.5	8.0	1.5	9.0	ns
t <sub>PLH</sub>	A <sub>n</sub> to B <sub>n</sub> or B <sub>n</sub> to A <sub>n</sub>	1.5	8.0	1.5	9.0	
t <sub>PZL</sub>	Output Enable Time	1.5	10.0	1.5	11.0	ns
t <sub>PZH</sub>		1.5	10.0	1.5	11.0	
t <sub>PLZ</sub>	Output Disable Time	1.5	8.0	1.5	9.0	ns
t <sub>PHZ</sub>		1.5	8.0	1.5	9.0	
t <sub>OSHL</sub>	Output to Output Skew		1.0		1.0	ns
t <sub>OSLH</sub>	(Notes 4, 5)		1.0		1.0	

Note 4: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH to LOW  $(t_{OSHL})$  or LOW to HIGH  $(t_{OSLH})$ .

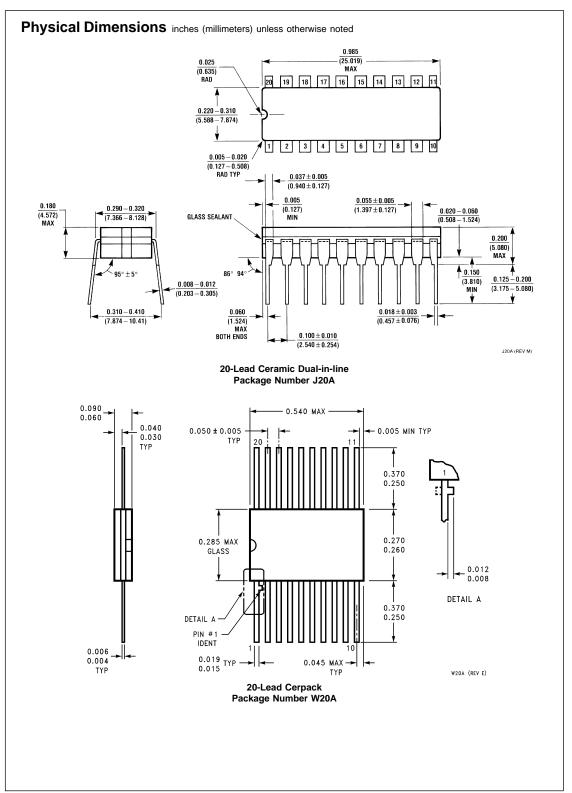
Note 5: Guaranteed but not tested (design characterization data).

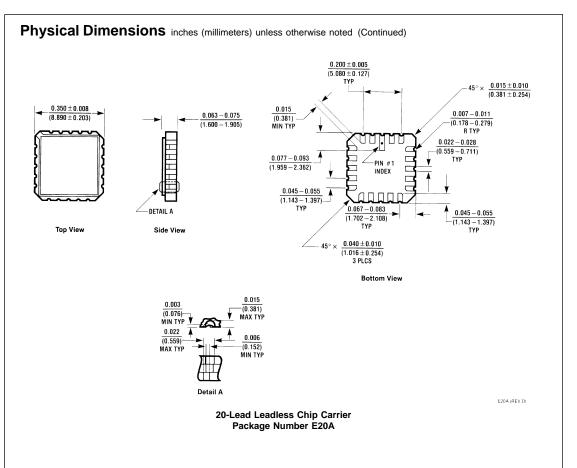
### **Dynamic Switching Characteristics**

Symbol	Parameter	Conditions	V <sub>CC</sub>	T <sub>A</sub> = 25°C	Units
V <sub>OLP</sub>	Quiet Output Dynamic Peak V <sub>OL</sub>	C <sub>L</sub> = 50 pF, V <sub>IH</sub> = 3.0V, V <sub>IL</sub> = 0V	(V) 3.0	<b>Max</b> 1.0	V
V <sub>OLV</sub>	Quiet Output Dynamic Valley V <sub>OL</sub>	C <sub>L</sub> = 50 pF, V <sub>IH</sub> = 3.0V, V <sub>IL</sub> = 0V	3.0	-0.8	V

### Capacitance

Symbol	Parameter	Conditions	Max	Units
C <sub>IN</sub>	Input Capacitance	V <sub>CC</sub> = Open, V <sub>I</sub> = 0V or V <sub>CC</sub>	10	pF
C <sub>I/O</sub>	Input/Output Capacitance	$V_{CC} = 3.3V$ , $V_{I} = 0V$ or $V_{CC}$	12	pF
C <sub>PD</sub>	Power Dissipation Capacitance	$V_{CC} = 3.3V$ , $V_{I} = 0V$ or $V_{CC}$ , $f = 10$ MHz	30	pF





#### LIFE SUPPORT POLICY

NATIONAL'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF NATIONAL SEMI-CONDUCTOR CORPORATION. As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
- A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



National Semiconductor Corporation Americas Tel: 1-800-272-9959

Tel: 1-800-272-9959 Fax: 1-800-737-7018 Email: support@nsc.com

www.national.com

National Semiconductor Europe

Fax: +49 (0) 1 80-530 85 86
Email: europe.support@nsc.com
Deutsch Tel: +49 (0) 1 80-530 85 85
English Tel: +49 (0) 1 80-532 78 32
Français Tel: +49 (0) 1 80-532 93 88
Italiano Tel: +49 (0) 1 80-534 16 80

National Semiconductor Asia Pacific Customer Response Group Tel: 65-2544466 Fax: 65-2504466 Email: sea.support@nsc.com National Semiconductor Japan Ltd. Tel: 81-3-5639-7560 Fax: 81-3-5639-7507